

FORM HDP-1449 (Based on Form PTO-1449)		ATTORNEY DOCKET NO.	SERIAL NO.
PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		5077-000069/DVA	10/617,198
		APPLICANT	
		Kenya Uomori et al.	
		FILING DATE	GROUP
		07/10/2003	AU: 2875
Sheet 1 of 1			

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/Subclass	(If appropriate) Filing Date
1.	JC	4,294,544	10/1981	Altschuler et al.		
2.	JC	4,427,880	01/1984	Kanade et al.		
3.	JC	4,594,001	06/1986	DiMatteo et al.		
4.	JC	4,687,325	08/1987	Corby, Jr., Nelson R.		
5.	JC	4,867,570	09/1989	Sorimachi et al.		
6.	JC	4,871,256	10/1989	Grindon, John R.		
7.	JC	5,930,383	07/1999	Netzer, Yishay		
8.	JC	6,392,744	05/2002	Holec, Henry V.		
9.	JC	6,441,888	08/2002	Azuma et al.		

FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/Subclass	Translation Yes	Translation No
1.							

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	JC	Inokuchi, Seiji; "Recent trend of Development and Application in Range Imaging"; MVA '98 IAPR Workshop on Machine Vision Applications; pp. 359-366; November 17-19, 1998.

Examiner: /Jacob Choi/ (08/15/2006)

Date Considered: 08/15/2006

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	JC	2000241131 A	09/08/2000	Japan		Abstract	
2.	JC	08178632 A	07/12/1996	Japan		Abstract	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
1.	JC	11-023225	01/29/1999	Japan		Abstract
2.	JC	04-241476	08/28/1992	Japan		Abstract

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)						
Ref. Desig.	Examiner's Initials					
1.	JC	Notice of Reasons of Rejection for Japanese Patent Application No. 2001-286646; Mailed: August 31, 2004; and English translation.				

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